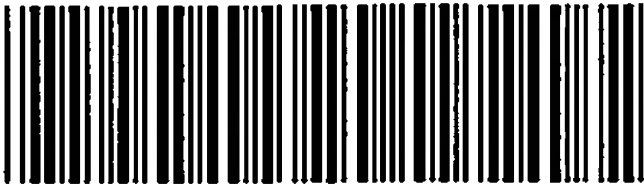


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/615,476	DUPAQUIS ET AL.	
	Examiner	Art Unit	
	Tan V. Mai	2193	

SEARCHED			
Class	Subclass	Date	Examiner
708	620-625, 491-492	6/27/2006	MAI

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Inventor search Double Patenting Check Data Bases Search (see search history printout)	6/27/2006	MAI